

Configuration Manual

MSc Research Project Data Analytics

Michael Ward Student ID: x20190212

School of Computing National College of Ireland

Supervisor:

Zahid Iqbal

National College of Ireland

MSc Project Submission Sheet



Year: 2022

School of Computing

Student Michael Ward Name:

Student ID: x20190212

Student ID: x20190212

Programme: MSc in Data Analytics

Module: MSc Research Project

Supervisor: Zahid Iqbal Submission

Due Date: 15/12/22

Project Title: Automated Detection of Semi-Conductor Wafer Map Defects Using Machine Learning Techniques

Word Count: Page Count:

I hereby certify that the information contained in this (my submission) is information pertaining to research I conducted for this project. All information other than my own contribution will be fully referenced and listed in the relevant bibliography section at the rear of the project.

<u>ALL</u> internet material must be referenced in the bibliography section. Students are required to use the Referencing Standard specified in the report template. To use other author's written or electronic work is illegal (plagiarism) and may result in disciplinary action.

Signature:

Date:

PLEASE READ THE FOLLOWING INSTRUCTIONS AND CHECKLIST

Attach a completed copy of this sheet to each project (including multiple copies)	
Attach a Moodle submission receipt of the online project	
submission, to each project (including multiple copies).	
You must ensure that you retain a HARD COPY of the project, both	
for your own reference and in case a project is lost or mislaid. It is not	
sufficient to keep a copy on computer.	

Assignments that are submitted to the Programme Coordinator Office must be placed into the assignment box located outside the office.

Office Use Only

Signature:	
Date:	

Penalty Applied (if applicable):	

Configuration Manual

Michael Ward Student ID: x20190212

1 Introduction

This configuration manual covers the specifications needed to successfully replicate the project. Each is laid out in a step-by-step manner that will enable implementation of the research project "Automated Detection of Semi-Conductor Wafer Map Defects Using Machine Learning Techniques".

2 System configuration

2.1 Software Specification

- Windows 10 operating system
- Spyder Integrated Development Environment (IDE)

2.2 Hardware Specification

- HP ZBOOK PC
- Intel(R) Core(TM) i7-8850H CPU @ 2.60GHz 2.59 GHz
- 48.0 GB Ram
- Nvidia Quadro P1000

2.3 Prerequisites¹

- NVIDIA® GPU card with CUDA® architectures 3.5, 5.0, 6.0, 7.0, 7.5, 8.0 and higher
- Goto <u>https://developer.nvidia.com/cuda-gpus</u> to check if your card is compatible
- Python 3.7–3.10
- pip version 19.0 or higher for Linux (requires manylinux2010 support) and Windows. pip version 20.3 or higher for macOS.
- Windows Native Requires Microsoft Visual C++ Redistributable for Visual Studio 2015, 2017 and 2019
- NVIDIA® GPU drivers version 450.80.02 or higher.
- CUDA® Toolkit 11.2.
- cuDNN SDK 8.1.0.
- (Optional) TensorRT to improve latency and throughput for inference.

¹ <u>https://www.tensorflow.org/install/pip</u>

3 Implementation

3.1 Code Set Up

The code was developed in the Spyder IDE. It allowed for a more robust development experience for python.



Follow the below steps set up the project.

- 1. Open Research_project.zip
- 2. The folder contains 5 items.
- 3. Extract the contents to any directory as seen in Figure 1.
- 4. Download the dataset from

^	Name ~	Туре	Compressed size	Password (
	📕 watchDir	File folder			
	🝺 1_Analytics_and_data_generatio	Python File	8 KB	No	
	2_Detection_App.py	Python File	2 KB	No	
	🔋 LSWMD.zip	Compressed (zipped) Fol	144,380 KB	No	
	my_model.h5	H5 File	33,553 KB	No	

Figure 1 project zip contents

- 5. Download the dataset from <u>here</u>
- 6. Place the zip file in the same directory as the python files
- 7. Once extracted you have two options. You can open the full project and run the analytical and data generation code. Or you can open the app and load the pre saved model. The zip also contains test maps for quick use with the second python file.

3.2 WatchDir

This is a directory where the automated checking of the app will constantly look for a test.png file.

3.3 1_Analytics_and_data_generation.py

The file contains a total of 16 functions

- def find_and_read_file()
- def perform_analytics()
- def data_cleaning()
- def wafer_generation()
- def cal_den()
- def change_val()
- def cubic_inter_mean()
- def cubic_inter_mean()
- def find_regions()
- def cal_dist()
- def fea_geom()
- def plot_confusion_matrix()

Running this file will automatically do the analytics and generate and manipulate the data set.

3.3.1 Packages

Below in figure 2 is a list of all packages used in the Analytics_and_data_generation.py.

```
#%% Importing packages
import numpy as np
import pandas as pd
import matplotlib.pyplot as plt
import os
from sklearn.metrics import confusion_matrix
from sklearn.model_selection import train_test_split
from tensorflow import keras
import warnings
from pathlib import Path
import zipfile
from skimage import measure
from skimage.transform import radon
from scipy import interpolate
from scipy import stats
import theano
from theano import tensor as T
from keras.utils import np_utils
from matplotlib import gridspec
import itertools
from sklearn.metrics import classification_report
import tensorflow as tf
from tensorflow.keras import layers
from tensorflow.keras.models import Sequential
```

Figure 2 imported packages

3.3.2 Functions()

Function looks to see if the dataset exists, if not then it will extract it from the zip file and add it to a data frame as seen from figure 3 below.



Figure 3 def find_and_read_file()

This function plots a bar chart of the wafer frequency as seen in figure 4.

```
def perform_analytics(df):
    uni_Index=np.unique(df.waferIndex, return_counts=True)
    plt.bar(uni_Index[0],uni_Index[1], color='blue', align='center', alpha=0
    plt.xlabel("Number of wafers")
    plt.ylabel("frequency")
    plt.xlim(0,26)
    plt.ylim(30000,35000)
    plt.show()
perform_analytics(df)
```

Figure 4 perform_analytics()

runs data cleaning and finds the dimensions of the wafers.

```
def data_cleaning(df):
    df = df.drop(['waferIndex'], axis = 1)
    def find_dim(x):
        dim0=np.size(x,axis=0)
        dim1=np.size(x,axis=1)
        return dim0,dim1
    df['wmDim']=df.waferMap.apply(find_dim)
    print(df.sample(5))
    print("Max Dim: ",max(df.wmDim), " Min Dim:", min(df.wm
    uni_waferDim=np.unique(df.wmDim, return_counts=True)
    uni_waferDim[0].shape[0]
    return(df)
```

Figure 5 data cleaning

This function is to big to fit into a figure so only partial code is show in figure 6.



Figure 6 wafer_generation()

The cal_den() function helps calculate the wafer density as shown in figure 7.



Figure 7 cal_den()

Below function calculates the regions on the wafer as shown in figure 8.

```
def find_regions(x):
    rows=np.size(x,axis=0)
    cols=np.size(x,axis=1)
    ind1=np.arange(0,rows,rows//5)
    ind2=np.arange(0,cols,cols//5)
    reg1=x[ind1[0]:ind1[1],:]
    reg3=x[ind1[4]:,:]
    reg4=x[:,ind2[0]:ind2[1]]
    reg2=x[:,ind2[4]:]
    reg5=x[ind1[1]:ind1[2],ind2[1]:ind2[2]]
    reg6=x[ind1[1]:ind1[2],ind2[2]:ind2[3]]
    reg7=x[ind1[1]:ind1[2],ind2[3]:ind2[4]]
    reg8=x[ind1[2]:ind1[3],ind2[1]:ind2[2]]
    reg9=x[ind1[2]:ind1[3],ind2[2]:ind2[3]]
    reg10=x[ind1[2]:ind1[3],ind2[3]:ind2[4]]
    reg11=x[ind1[3]:ind1[4],ind2[1]:ind2[2]]
    reg12=x[ind1[3]:ind1[4],ind2[2]:ind2[3]]
    reg13=x[ind1[3]:ind1[4],ind2[3]:ind2[4]]
    fea reg den = []
    fea_reg_den = [cal_den(reg1), cal_den(reg2)
    return fea_reg_den
```

Figure 8 find regions

Below functions are used for the calculation of the radon transforms.



Figure 9 cubic inter mean

Below code is used for the calculation and extraction of densirt based features.

```
def fea geom(img):
   norm_area=img.shape[0]*img.shape[1]
    norm_perimeter=np.sqrt((img.shape[0])**2+(img.shape[1])**2)
    img labels = measure.label(img, connectivity=1, background=0)
    if img_labels.max()==0:
       img labels[img labels==0]=1
       no_region = 0
        info_region = stats.mode(img_labels[img_labels>0], axis = None)
       no_region = info_region[0][0]-1
    prop = measure.regionprops(img_labels)
    prop_area = prop[no_region].area/norm_area
   prop_perimeter = prop[no_region].perimeter/norm_perimeter
   prop_cent = prop[no_region].local_centroid
   prop_cent = cal_dist(img,prop_cent[0],prop_cent[1])
   prop_majaxis = prop[no_region].major_axis_length/norm_perimeter
   prop_minaxis = prop[no_region].minor_axis_length/norm_perimeter
    prop_ecc = prop[no_region].eccentricity
    prop_solidity = prop[no_region].solidity
```

```
return prop_area,prop_perimeter,prop_majaxis,prop_minaxis,prop_ecc,prop_solidity
```

Figure 10 fea geom

```
# One-Vs-One
from sklearn.svm import LinearSVC
from sklearn.multiclass import OneVsOneClassifier
clf2 = OneVsOneClassifier(LinearSVC(random_state = RANDOM_STATE)).fit(X_train, y_train)
print(X_train)
y_train_pred = clf2.predict(X_train)
y_test_pred = clf2.predict(X_test)
train_accuracy2 = np.sum(y_train == y_train_pred, axis=0, dtype='float') / X_train.shape[0]
print(train_accuracy2)
test_accuracy2 = np.sum(y_test == y_test_pred, axis=0, dtype='float') / X_test.shape[0]
print('One-Vs-One Training accuracy: {}'.format(X_train*100))
print('One-Vs-One Testing accuracy: {}'.format(X_test*100))
print("y_train_pred[:100]: ", y_train_pred[:100])
print ("y_train[:100]: ", y_train[:100])
print(X_test)
def plot_confusion_matrix(cm, normalize=False, title='Confusion matrix', cmap=plt.cm.Blues):
    This function prints and plots the confusion matrix.
    Normalization can be applied by setting `normalize=True`.
    if normalize:
        cm = cm.astype('float') / cm.sum(axis=1)[:, np.newaxis]
        print("Normalized confusion matrix")
        print('Confusion matrix, without normalization')
    plt.imshow(cm, interpolation='nearest', cmap=cmap)
    plt.title(title)
    plt.colorbar()
    fmt = '.2f' if normalize else 'd'
    thresh = cm.max() / 2.
    for i, j in itertools.product(range(cm.shape[0]), range(cm.shape[1])):
        color="white" if cm[i, j] > thresh else "black")
    plt.tight_layout()
    plt.ylabel('True Defect')
plt.xlabel('Predicted Defect')
```

Figure 11 SVM classification

Above code is use the create the SVM mode and plot the confusion matrix.



Figure 12 confusion matrix

3.3.3 Sequential Neural Network

The next part of the code is in relation to the sequential neural network. Figure 13 below shows a partial amount of the code. It imports a local dataset that is generated in a previous function. It will import that data and perform a data analysis and train the neural network.

# Neural Network	
data_dir = os.path.abspath('C:/Users/wardmich/OneDrive - Intel Corporation/Documents/Final_project_and_Thesis/	Project/data')
print(data_dir)	
batch_size = 32 img_height = 180 img_width = 180	
<pre>train_ds = tf.keras.utils.image_dataset_from_directory(data_dir, validation_split=0.2, subset="training", seed=123, image_size=(img_height, img_width), batch_size=batch_size)</pre>	
<pre>val_ds = tf.keras.utils.image_dataset_from_directory(data_dir, validation_split=0.2, subset="validation", seed=123, image_size=(img_height, img_width), batch_size=batch_size)</pre>	
class_names = train_ds.class_names print(class_names)	
import matplotlib.pyplot as plt	
<pre>plt.figure(figsize=(10, 10)) for images, labels in train_ds.take(1): for i in range(9): ax = plt.subplot(3, 3, i + 1) plt.imshow(images[i].numpy().astype("uint8")) plt.title(class_names[labels[i]]) plt.axis("off")</pre>	
<pre>for image_batch, labels_batch in train_ds: print(image_batch.shape) print(labels_batch.shape) break</pre>	

Figure 13 sequential model

3.4 2_Detection_App.py

This is the second python file. It contains the developed application. It uses the Tkinter package to make the create the graphical user interface. This file can be ran independently of the first python file as it will import a presaved model named "My_Model". Below figure.



Figure 14

Once the code is executed, the GUI will pop up. From here, the user has two options as seen below in figure 15. When the user clicks the Manual wafer map inspection button, they call browse to wherever they have wafer maps stored. Click on the wafer map and import it into the detection app.

Figure 15 option selection

The user will then be presented with the screen as shown below in figure 16. It shows the wafer map that the user loaded. The salient version of the wafer map and the classification of the wafer map with an accuracy percentage displayed at the top of the app window. Next, if

the user clicks the Automated wafer map inspection, it will scan the WatchDir folder for new test.png wafer maps. An alert will display under the results label that Auto Watch is active, as seen from figure 17 below.

Figure 16 Detection app

Figure 17 Auto watch enabled

3.5 LSWMD.zip

This zip file contains a compressed version of the dataset at a size of 157,513KB. When extracted it contains the LSWMD.pkl dataset. The decompressed size of this dataset is 2,046,393KB.

3.6 my_model.h5

This is the sequential model saved in a .h5 format. The model can be easily reloaded for use with the app.